Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,947	LEE ET AL.
Examiner	Art Unit
Benjamin E. Lanier	2132

SEARCHED					
Class	Subclass	Date	Examiner		
			•		
			·- · · · · ·		
:					
	,				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		<del></del> ,		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
		Ī		
East Search	6/20/2007	#		
See Attachment	6/20/2007			
		·		
**************************************				
	,			
	- 10			